



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

ATTY. DOCKET NO.
50099-254

SERIAL NO.
10/830,090

APPLICANT
Tohru KOYAMA, et al.

FILING DATE
April 23, 2004

GROUP
2825

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
/AV/		US 5,208,648	5/4/1993	INTERNATIONAL BUSINESS MACHINES CORPORATION	Corresponds to JP 5-157701
/AV/		US 10/684,507 copy of claims and drawings	Filed 10/15/03		
/AV/		US 10/697,277 copy of claims and drawings	Filed 10/31/2003		
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/AV/		JP 2002-18900 A	7/5/2002	NEC CORP		w/English Abstract	
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
/AV/		EJI YOSHIDA ET AL., "High Resolution Laser Voltage Probing", collection of drafts, LSI testing symposium, ULSI Development Center, Evaluation and Analysis Department, Mitsubishi Electric Corporation, pp. 143-147, 2002
/AV/		S.B. IPPOLITO ET AL., "High Spatial Resolution Subsurface Microscopy", Applied Physics Letters, Vol. 87, No. 26, June 25, 2001, pp. 4071-4073
/AV/		H. TERADA, "Effectiveness of Solid Immense Lens", a document from the 14th Semiconductor Workshop Discourse hosted by Hamamatsu Photonics K.K., pp. 1-3, 2003

EXAMINER
/Arleen Vazquez/

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08/17/2007

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